

# APPROVAL SHEET

MULTILAYER CERAMIC CAPACITORS

High Q / Low ESR Series (HH)

0402, 0603 & 0805 Sizes

**NP0** Dielectric

**RoHS Compliance** 

\*Contents in this sheet are subject to change without prior notice.



#### 1. INTRODUCTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC HH series MLCC is used at high frequencies generally have a small temperature coefficient of capacitance, typical within the ±30ppm/°C required for NP0 (C0G) classification and have excellent conductivity internal electrode. Thus, WTC HH series MLCC will be with the feature of low ESR and high Q characteristics.

## 2. FEATURES

- a. High Q and low ESR performance at high frequency.
- b. Quality improvement of telephone calls for low power loss and better performance.

#### 3. APPLICATIONS

- a. Mobile telecommunication: Mobile phone, WLAN.
- b. RF module: Power amplifier, VCO.
- c. Tuners.

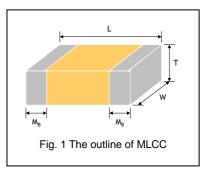
## 4. HOW TO ORDER

<u>HH</u>	<u>15</u>	<u>N</u>	<u>100</u>	<u>G</u>	<u>500</u>	<u>C</u>	I
<u>Series</u>	<u>Size</u>	Dielectric	<u>Capacitance</u>	Tolerance	Rated voltage	<u>Termination</u>	<u>Packaging</u>
<b>HH</b> =High Q/ Low ESR	<b>15</b> =0402 (1005) <b>18</b> =0603 (1608) <b>21</b> =0805 (2012)	<b>N</b> =NP0 (C0G)	Two significant digits followed by no. of zeros. And R is in place of decimal point.	B=±0.1pF C=±0.25pF D=±0.5pF F=±1% G=±2%	Two significant digits followed by no. of zeros. And R is in place of decimal point.	L=Ag/Ni/Sn C=Cu/Ni/Sn	T=7" reeled G=13" reeled
			eg.: R47=0.47pF 0R5=0.5pF 1R0=1.0pF 100=10x10 <sup>0</sup> =10pF	<b>J</b> =±5%	160=16 VDC 250=25 VDC 500=50 VDC 101=100 VDC 201=200 VDC 251=250 VDC 501=500 VDC 631=630 VDC		



## **5. EXTERNAL DIMENSIONS**

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		Remark	M <sub>B</sub> (mm)
0402 (1005)	1.00±0.05	0.50±0.05	0.50±0.05	N	#	0.25 +0.05/-0.10
0000 (4000)	1.60±0.10	0.80±0.10	0.80±0.07	s		0.40.045
0603 (1608)	1.60 +0.15/-0.10	0.80 +0.15/-0.10	0.80 +0.15/-0.10	х		0.40±0.15
			0.60±0.10	Α		
0805 (2012)	2.00±0.15	1.25±0.10	0.80±0.10	В		0.50±0.20
			1.25±0.10	D	#	



## **6. GENERAL ELECTRICAL DATA**

Dielectric	NP0		
Size	0402, 0603, 0805		
	0402: 0.5pF to 470pF**		
Capacitance*	0603: 0.5pF to 3300pF		
	0805: 0.5pF to 390pF		
	Cap≤5pF: B (±0.1pF), C (±0.25pF)		
Capacitance tolerance	5pF <cap<10pf: (±0.25pf),="" (±0.5pf)<="" c="" d="" td=""></cap<10pf:>		
	Cap≥10pF: F (±1%), G (±2%), J (±5%)		
Rated voltage (WVDC)	16V, 25V, 50V, 100V, 200V, 250V, 500V, 630V		
Q*	Cap<30pF: Q≥400+20C		
ď	Cap≥30pF: Q≥1000		
Insulation resistance at Ur	≥10GΩ or RxC≥100Ω-F whichever is smaller.		
Operating temperature	-55 to +125℃		
Capacitance change ±30ppm			
Termination	Ni/Sn (lead-free termination)		

 $<sup>^{\</sup>star}$  Measured at the conditions of 25°C ambient temper ature and 30~70% related humidity.

Apply 1.0±0.2Vrms, 1.0MHz±10% for Cap≤1000pF and 1.0±0.2Vrms, 1.0kHz±10% for Cap>1000pF.

<sup>#</sup> Reflow soldering only is recommended.

<sup>\*\* 0402,</sup> Capacitance <0.5pF: On request.



# 7. CAPACITANCE RANGE

	DIELECTRIC							NP0						
	SIZE		0402			06		-			08	05		
	Rated Voltage	16	25	50	16	25	50	100	50	100	200	250	500	630
	0.5pF (0R5)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.6pF (0R6)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.7pF (0R7)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.8pF (0R8)	N^	N^	N^	S^	S^	S^	S^	В	В				
	0.9pF (0R9)	N^	N^	N^	S^	S^	S^	S^	В	В				
	1.0pF (1R0)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	1.2pF (1R2)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	1.5pF (1R5)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	1.8pF (1R8)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	2.2pF (2R2)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	2.7pF (2R7)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	3.3pF (3R3)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	3.9pF (3R9)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	4.7pF (4R7)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	5.6pF (5R6)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	6.8pF (6R8)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	8.2pF (8R2)	N^	N^	N^	S^	S^	S^	S^	В	В	В	В	В	В
	10pF (100)	N	N	N	S	S	S	S	В	В	В	В	В	В
	12pF (120)	N	N	N	S	S	S	S	В	В	В	В	В	В
	15pF (150)	N	N	N	S	S	S	S	В	В	В	В	В	В
	18pF (180)	N	N	N	S	S	S	S	В	В	В	В	В	В
	22pF (220)	N	N	N	S	S	S	S	В	В	В	В	В	В
Capacitance	27pF (270)	N	N	N	S	S	S	S	В	В	В	В	В	В
ita	33pF (330)	N	N	N	S	S	S	S	В	В	В	В	В	В
bac	39pF (390)	N	N	N	S	S	S	S	В	В	В	В	В	В
င်ဒ	47pF (470)	N	N	N	S	S	S	S	В	В	В	В	В	В
	56pF (560)	N	N	N	S	S	S	S	В	В	В	В	В	В
	68pF (680)	N	N	N	S	S	S	S	В	В	В	В	В	В
	82pF (820)	N	N	N	S	S	S	S	В	В	В	В	В	В
	100pF (101)	N	N	N	S	S	S	S	В	В	В	В	В	В
	120pF (121)	N	N	N	S	S	S	S	D	D	D	D	D	D
	150pF (151)	N	N	N	S	S	S	S	D	D	D	D	D	D
	180pF (181)	N N	N	N	S	S	S	S			D	D	D	D
	220pF (221)	N N	N	N N	S S	S S	S S	S			D	D D	D D	D
	270pF (271) 330pF (331)	N N	N N	N N	S	S	S	S			D D	D	D	D D
	390pF (391)	N N	N	N N				S				D	D	
	470pF (471)	N N	N	N N	S S	S S	S S	S			D	ט	ט	D
	560pF (561)	IN	IN	IN	S	S	S	S						
	680pF (681)				S	S	S	S						
	820pF (821)				S	S	S	S						
	1,000pF (102)				S	S	S	S						
	1,200pF (102)				X	X	X							
	1,500pF (152)				X	X	X							
	1,800pF (182)				X	X	X							
	2,200pF (222)				X	X	X							
	2,700pF (272)				X	X	X							
	3,300pF (332)				X	X	X							
	3,300pr (332)				^	^	^							1

<sup>1.</sup> The letter in cell is expressed the symbol of product thickness.

<sup>2.</sup> The letter in cell with "A" mark is expressed product with Ag/Ni/Sn terminations.

<sup>3. 0402,</sup> Capacitance <0.5pF: On request.

<sup>4.</sup> For more information about products with special capacitance or other data, please contact WTC local representative.



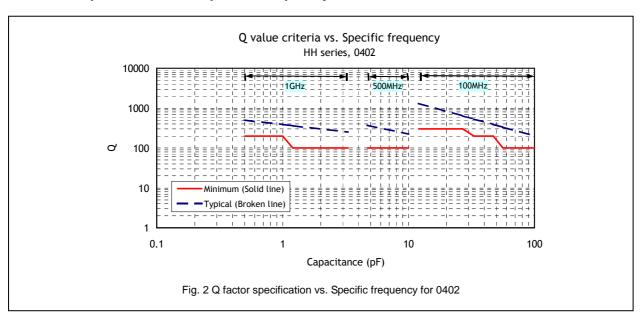
## **8. PACKAGING DIMENSION AND QUANTITY**

Size	Thickness (mm)/Syml	ickness (mm)/Symbol		r tape	Plastic tape	
Size	THICKIESS (IIIII)/Sylli	001	7" reel	13" reel	7" reel	13" reel
0402	0.50±0.05	N	10K	50K		
0603	0.80±0.07	S	4K	15K		
0003	0.80 +0.15/-0.10	X	41			
	0.60±0.10	Α	4k	15k		
0805	0.80±0.10	В	4K			
	1.25±0.10	D			3k	10k

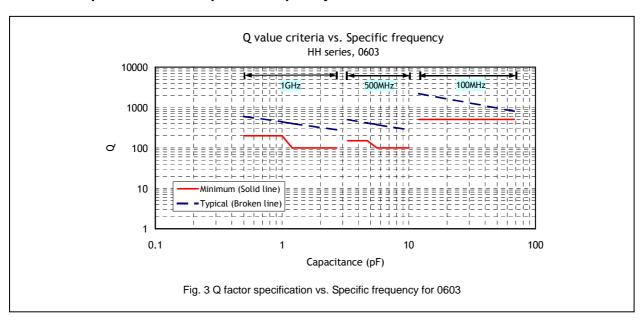
Unit: pieces

## 9. ELECTRICAL CHARACTERISTICS

### **Q** factor specification vs. Specific frequency

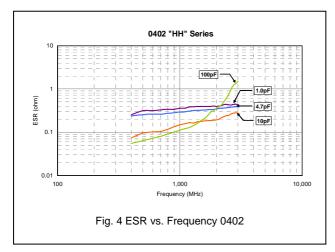


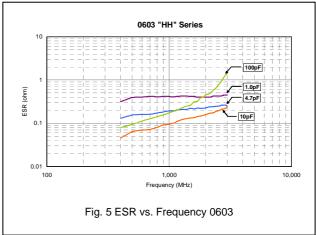
## Q factor specification vs. Specific frequency



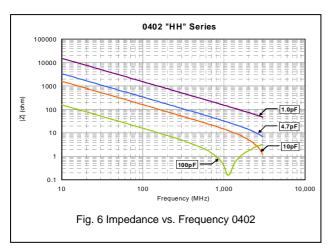


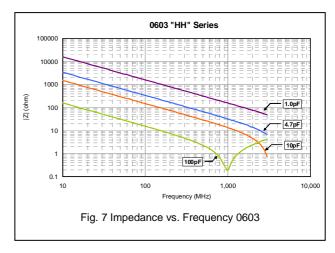
## **■** Typical ESR vs. Frequency



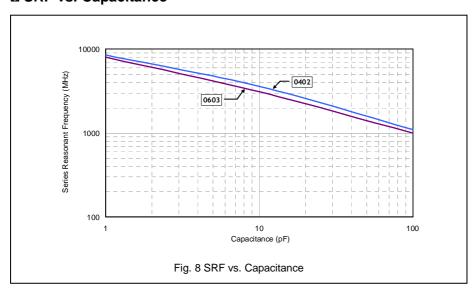


## **■** Typical Impedance vs. Frequency





## **■** SRF vs. Capacitance





# 10. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

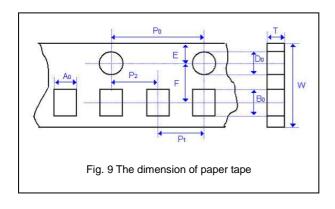
No.	Item	Test Conditions	Requirements
1.	Visual and		* No remarkable defect.
	Mechanical		* Dimensions to conform to individual specification sheet.
2.	Capacitance		* Shall not exceed the limits given in the detailed spec.
3.	Q/ D.F.	Cap>1000pF, 1.0±0.2Vrms, 1KHz±10%	* NP0: Cap≥30pF, Q≥1000; Cap<30pF, Q≥400+20C
	(Dissipation	At 25℃ ambient temperature.	
	Factor)		
4.	Dielectric	* To apply voltage: ( ≤100V ) 250% of rated voltage.	* No evidence of damage or flash over during test.
	Strength	* Duration: 1 to 5 sec.	
		* Charge and discharge current less than 50mA.	
		* To apply voltage:	
		200V~300V ≥2 times VDC	
		500V~999V ≥1.5 times VDC	
		* Cut-off, set at 10mA	
		* TEST= 15 sec.	
		* RAMP=0	
5.	Insulation	Rated voltage:<200V	≥10GΩ
	Resistance	To apply rated voltage for max. 120 sec.	
		Rated voltage:200~630V	≥10GΩ or RxC≥100Ω-F whichever is smaller
		To apply rated voltage (500V max.) for 60 sec.	
6.	Temperature	With no electrical load.	* Capacitance change: within ±30ppm/℃
	Coefficient	Operating temperature: -55~125℃ at 25℃	
7.	Adhesive	* Pressurizing force :	* No remarkable damage or removal of the terminations.
	Strength of	5N (≤0603) and 10N (>0603)	
	Termination	* Test time: 10±1 sec.	
8.	Vibration	* Vibration frequency: 10~55 Hz/min.	* No remarkable damage.
	Resistance	* Total amplitude: 1.5mm	* Cap change and Q/D.F.: To meet initial spec.
		* Test time: 6 hrs. (Two hrs each in three mutually	
		perpendicular directions.)	
		* Measurement to be made after keeping at room temp. for	
		24±2 hrs.	
9.	Solderability	* Solder temperature: 235±5℃	95% min. coverage of all metalized area.
		* Dipping time: 2±0.5 sec.	
10.	Bending Test	* The middle part of substrate shall be pressurized by means	* No remarkable damage.
		of the pressurizing rod at a rate of about 1 mm per second until	* Cap change: within ±5.0% or ±0.5pF whichever is larger.
		the deflection becomes 1 mm and then the pressure shall be	(This capacitance change means the change of capacitance under
		maintained for 5±1 sec.	specified flexure of substrate from the capacitance measured before
		* Measurement to be made after keeping at room temp. for	the test.)
		24±2 hrs.	
11.	Resistance to	* Solder temperature: 260±5℃	* No remarkable damage.
	Soldering Heat		* Cap change: within ±2.5% or ±0.25pF whichever is larger.
		* Preheating: 120 to 150℃ for 1 minute before imme rse the	* Q/D.F., I.R. and dielectric strength: To meet initial requirements.
		capacitor in a eutectic solder.	* 25% max. leaching on each edge.
		* Before initial measurement (Class II only): Perform	
		150+0/-10℃ for 1 hr and then set for 24±2 hrs at r oom temp.	
		* Measurement to be made after keeping at room temp. for	
		24±2 hrs.	

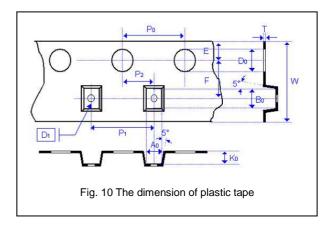
No.	ltem		Test Conditio	n	Requirements		
12.	Temperature	* Conduc	t the five cycles according to the	ne temperatures and	No remarkable damage.		
	Cycle	Step	Temp. (℃)	Time (min.)	*Cap change: within ±2.5% or ±0.25pF whichever is larger.		
		1	Min. operating temp. +0/-3	30±3	* Q/D.F., I.R. and dielectric strength: To meet initial requirements.		
		2	Room temp.	2~3			
		3	Max. operating temp. +3/-0	30±3			
		4	Room temp.	2~3			
		* Before i	* Before initial measurement (Class II only): Perform				
		150+0/-10	0℃ for 1 hr and then set for 24	±2 hrs at r oom temp.			
		* Measur	ement to be made after keepin	g at room temp. for			
		24±2 hrs.					
13.	Humidity	* Test ten	np.: 40±2℃		* No remarkable damage.		
	(Damp Heat)	* Humidit	y: 90~95% RH		* Cap change: within ±5.0% or ±0.5pF whichever is larger.		
	Steady State	* Test tim	e: 500+24/-0hrs.		* Q/D.F. value:		
		*Before ir	Before initial measurement (Class II only): Perform NP0: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275+2.5C				
		150+0/-10	0℃ for 1 hr and then set for 24	±2 hrs at room temp.	Cap<10pF; Q≥200+10C		
		* Measur	ement to be made after keepin	g at room temp. for	* I.R.: ≥1GΩor RxC≥50Ω-F whichever is smaller.		
		24±2 hrs.					
14.	Humidity	* Test ten	np.: 40±2℃		* No remarkable damage.		
	(Damp Heat)	* Humidit	y: 90~95%RH		* Cap change: within ±7.5% or ±0.75pF whichever is larger.		
	Load	* Test time: 500+24/-0 hrs.			* Q/D.F. value:		
		* To apply	y voltage: rated voltage (Max.	500V)	NP0: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C		
			nitial measurement (Class II or	**	* I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller.		
		voltage fo	or 1hr at 40℃ and then set for 2	24±2 hrs at room temp.			
		* Measur	ement to be made after keepin	g at room temp. for			
		24±2 hrs	S				
15.	High	* Test ten	np.:		* No remarkable damage.		
	Temperature	NP0: 12	25±3℃		* Cap change: within ±3.0% or ±0.3pF whichever is larger.		
	Load	* To apply	y voltage:		* Q/D.F. value:		
	(Endurance)	(1) <500\	/: 200% of rated voltage.		NP0: Cap≥30pF, Q≥350		
		(2) 500V: 150% of rated voltage.			10pF≤Cap<30pF, Q≥275+2.5C		
		(3) ≥630V: 120% of rated voltage.			Cap<10pF, Q≥200+10C		
			e: 1000+24/-0 hrs.		* I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.		
		*Before ir	nitial measurement (Class II on	lly): To apply test			
		voltage fo	or 1hr at test temp. and then se	et for 24±2 hrs at room			
		temp.					
		1	ement to be made after keeping	g at room temp. for			
		24±2 hrs					



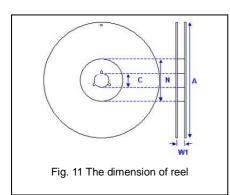
## **APPENDIXES**

## **■ Tape & reel dimensions**





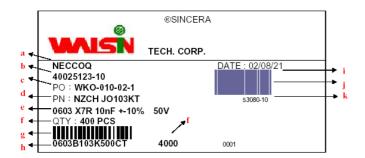
Size	0402	0603		0805	
Thickness	N	S, X	Α	В	C, D, I
A <sub>0</sub>	0.62±0.05	1.02±0.05	1.50±0.10	1.50±0.10	<1.57
B <sub>0</sub>	1.12±0.05	1.80±0.05	2.30±0.10	2.30±0.10	<2.40
Т	0.60±0.05	0.95±0.05	0.75±0.05	0.95±0.05	0.23±0.05
K <sub>0</sub>	-	-	-	-	<2.50
W	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10
P <sub>0</sub>	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10
10xP <sub>0</sub>	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10	40.0±0.10
P <sub>1</sub>	2.00±0.05	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10
$P_2$	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05
$D_0$	1.55±0.05	1.55±0.05	1.55±0.05	1.55±0.05	1.50±0.05
D <sub>1</sub>	-	-	-	-	1.00±0.10
E	1.75±0.05	1.75±0.05	1.75±0.05	1.75±0.05	1.75±0.10
F	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05	3.50±0.05



Size	0402, 0603, 0805					
Reel size	el size 7" 10"		13"			
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2			
$W_1$	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0			
Α	178.0±0.10	250.0±1.0	330.0±1.0			
N	60.0+1.0/-0	100.0±1.0	100±1.0			



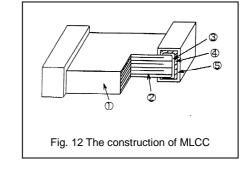
#### Description of customer label



- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

#### Constructions

No.	Na	me	NP0*	NP0
1	Ceramic	material	CaZrO <sub>3</sub> / Ba	aTiO₃ based
2	Inner el	ectrode	AgPd alloy	Ni
3		Inner layer	Ag	Cu
4	Termination	Middle layer	Ni	
(5)		Outer layer	S	Sn



<sup>\*</sup> Partial NP0 items are with Ag/Ni/Sn(NME) terminations, please ref to product range for detail.

#### Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

#### Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.



#### Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of  $N_2$  within oven are recommended.

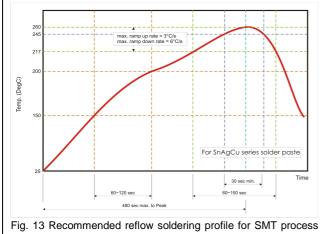


Fig. 13 Recommended reflow soldering profile for SMT process with SnAgCu series solder paste.

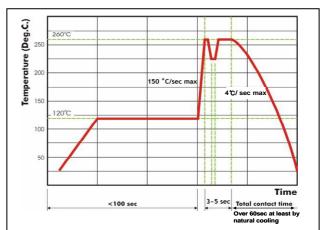


Fig. 14 Recommended wave soldering profile for SMT process with SnAgCu series solder.

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